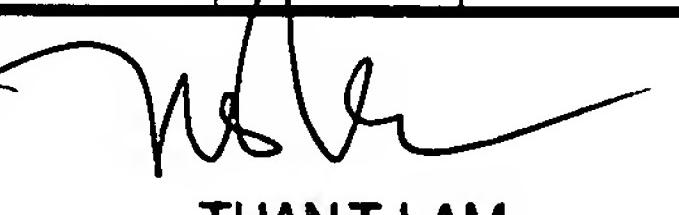


Issue Classification		
	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/710,673	LEE ET AL.
Examiner	Art Unit	
Hiep Nguyen	2816	

ORIGINAL		CROSS REFERENCE(S)						
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
327	589	327	306	331	332			
INTERNATIONAL CLASSIFICATION			361	91.1	18	98		
H	0	2	M	3/07				
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			/					
			/					
 TUAN T. LAM PRIMARY EXAMINER (Primary Examiner)							Total Claims Allowed: 13	
 Carol Smith (Legal Instruments Examiner)				6/29/06 (Date)			O.G. Print Claim(s)	O.G. Print Fig.
							1	2